Form PTO 1449 U.S. DEPARTMENT			OF COMMERCE	ATTY DOCKET NO.		SERIAL NO.			
(Modified)		PATENT AND TRAC	EMARK OFFICE	283236US2X PCT		10/560,070			
				APPLICANT					
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Hiroyuki OCHIAI, et al.					
				FILING DATE		GROUP			
				December 9, 2005		1793			
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		NUMBER	DATE	COUNTRY		YES		NO	
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	AZ	1			Additional References sheet(s) attached				
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